

Outline

- Computer generations and technology
- Cost of Integrated Circuits

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Computer Generations

Generation	Dates	Technology	Principal new Product
1	1950-1959	Vacuum Tubes	Commercial Electronic Computer
2	1960-1968	Transistors	Cheaper Computers
3	1969-1977	Integrated Circuit	Minicomputer
4	1978-?	LSI and VLSI	PC and workstations

Fig. 1.29 Page 42

Each generation is about 8-10 years long except the fourth

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Technology

Year	Technology used	Relative Performance/Unit Cost
1951	Vacuum Tube	1
1965	Transistor	35
1975	Integrated Circuit (IC)	900
1995	VLSI	2,400,000

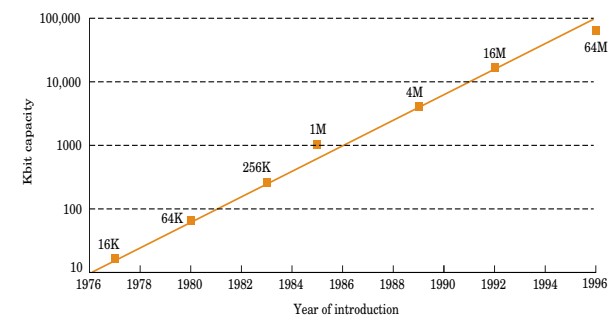
Fig. 1.13 Page 22

Transistor	On/Off switch controlled by electricity
IC	combine dozens to hundreds of transistors into a single chip
VLSI	Very-Large Scale Integrated circuit (millions of transistors)

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Growth in DRAM Capacity

- Example of increased integration
- Quadruple capacity every 3 years (DRAM growth rule)



1999 256 Mbit
2002 1 Gbit

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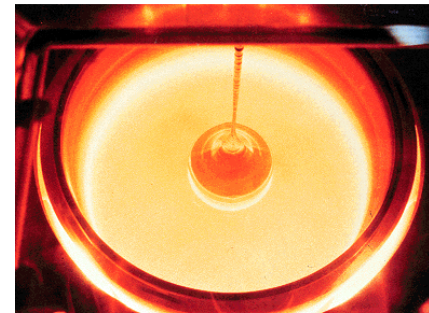
At The Beginning: Silicon

- Substance found in sand
- Does not conduct electricity well
- Apply special chemical process to obtain
 - ✓ Conductors of electricity
 - ✓ Insulators from electricity
 - ✓ Conduct or insulate under special conditions (transistors)

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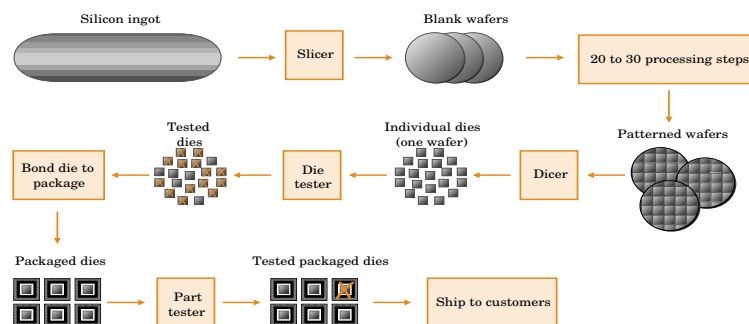
At The Beginning: Silicon

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Chip Manufacturing Process



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Yield = % of good dies from the total number of dies on the wafer

In Fig. Yield = $6/20 = 30\%$ (X means a bad die)

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Cost of Integrated Circuits

Refer to exercises 1.48-1.53 on pages 48-49

Cost per die = Cost per wafer / (Dies per wafer * yield)

Dies per wafer = Wafer area / Die area

Approximation (why?)

Yield = $1/(1 + (\text{Defect per area} * \text{Die area}/2))^2$

Empirical based on observation of yields

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Cost of Integrated Circuits

Example

Manufacturing a wafer costs \$1500

#of defects/cm² = 2.5

Wafer radius = 10 cm

Case A: dies are 1 cm * 1 cm

die area = 1 cm²

Dies per wafer = $\pi * R^2 / \text{Die area} = 3.14 * 10^2 / 1 = 314$ (an integer)

Yield = $1/(1 + \frac{1}{2} (2.5) (1.0))^2 = 0.198$

Cost per die = Cost per wafer / (Dies per wafer * yield) = $1500 / (314 * 0.198) = \$24.13$

Case B: dies are 2 cm * 2 cm

Die area = 4 cm²

Dies per wafer = $3.14 * 10^2 / 4 = 78.5 \rightarrow 78$ (integer)

Yield = 0.0278

Cost per die = $1500 / (78 * 0.0278) = \$691.75$

What do you observe here?

How does die area affect cost per die?

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Manufacturing Pentium chips



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Manufacturing Pentium chips

Fig. 1.16 & 1.17

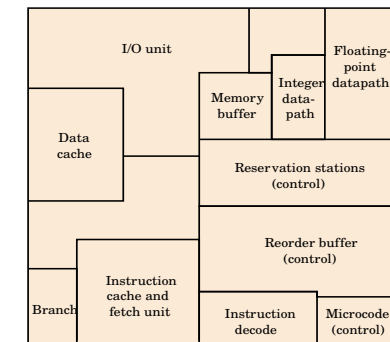
Pentium Pro die

5.5 million transistors

Cache is only 1 million transistors

Die area is 306 mm²

Pentium Pro packaged with an external cache with 31 million transistors (Fig. 1.19)



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Manufacturing Pentium chips

Fig. 1.16 & 1.17

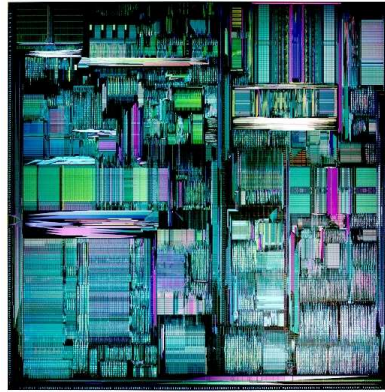
Pentium Pro die

5.5 million transistors

Cache is only 1 million transistors

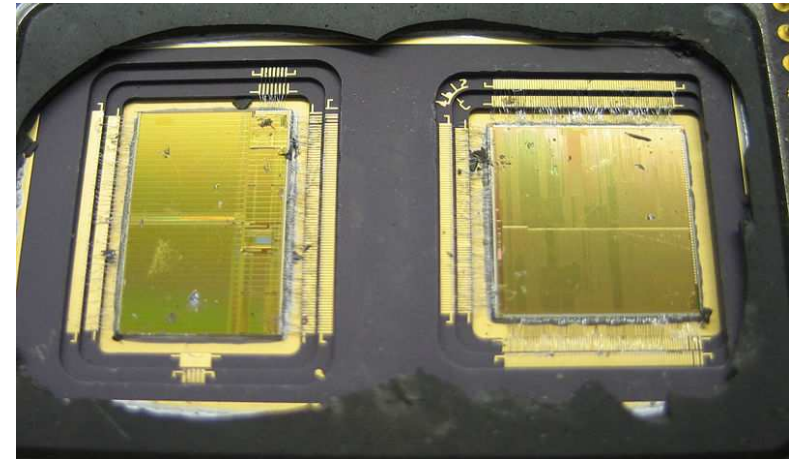
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Manufacturing Pentium chips



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